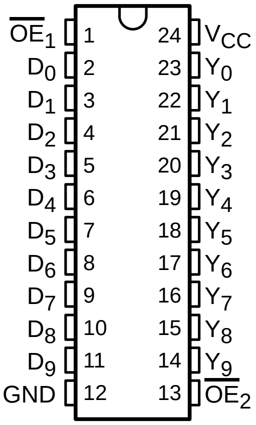
CY74FCT2827T
10-BIT BUFFER
WITH 3-STATE OUTPUTS

SCCS045A – MAY 1994 – REVISED SEPTEMBER 2001

- **Function and Pinout Compatible With FCT, F, and AM29827 Logic**
- **25-Ω Output Series Resistors Reduce Transmission-Line Reflection Noise**
- **Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions**
- **Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics**
- **I_{off} Supports Partial-Power-Down Mode Operation**
- **ESD Protection Exceeds JESD 22**
  - **2000-V Human-Body Model (A114-A)**
  - **200-V Machine Model (A115-A)**
  - **1000-V Charged-Device Model (C101)**
- **Matched Rise and Fall Times**
- **Fully Compatible With TTL Input and Output Logic Levels**
- **12-mA Output Sink Current**
  15-mA Output Source Current
- **3-State Outputs**

Q PACKAGE
(TOP VIEW)



description

The CY74FCT2827T 10-bit buffer provides high-performance bus-interface buffering for wide data/address paths or buses carrying parity. This 10-bit buffer has NANDed output-enable ($\overline{OE}$) inputs for maximum control flexibility. The CY74FCT2827T is designed for high-capacitance-load drive capability, while providing low-capacitance bus loading at both inputs and outputs. All inputs have clamp diodes and all outputs are designed for low-capacitance bus loading in the high-impedance state. On-chip termination resistors at the outputs reduce system noise caused by reflections. The CY74FCT2827T can replace the CY74FCT827T to reduce noise in an existing design.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

ORDERING INFORMATION

T_A	PACKAGE[†]		SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 85°C	QSOP – Q	Tape and reel	4.4	CY74FCT2827CTQCT	FCT2827C
	QSOP – Q	Tape and reel	8	CY74FCT2827ATQCT	FCT2827A

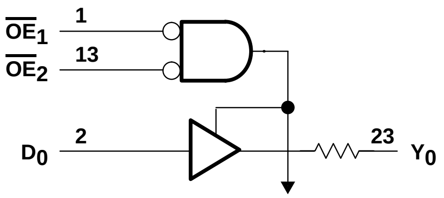
[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

INPUTS			OUTPUT Y	FUNCTION
$\overline{OE_1}$	$\overline{OE_2}$	D		
L	L	L	L	Transparent
L	L	H	H	
H	X	X	Z	3-State
X	H	X	Z	

H = High logic level, L = Low logic level, X = Don't care,
Z = High-impedance state

logic diagram (positive logic)



To Nine Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range to ground potential	–0.5 V to 7 V
DC input voltage range	–0.5 V to 7 V
DC output voltage range	–0.5 V to 7 V
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, θ_{JA} (see Note 1)	61°C/W
Ambient temperature range with power applied, T_A	–65°C to 135°C
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{OH}	High-level output current			–15	mA
I_{OL}	Low-level output current			12	mA
T_A	Operating free-air temperature	–40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			MIN	TYP[†]	MAX	UNIT
V_{IK}	V_{CC} = 4.75,	I_{IN} = –18 mA			–0.7	–1.2	V
V_{OH}	V_{CC} = 4.75,	I_{OH} = –15 mA		2.4	3.3		V
V_{OL}	V_{CC} = 4.75,	I_{OL} = 12 mA			0.3	0.55	V
R_{out}	V_{CC} = 4.75,	I_{OL} = 12 mA		20	25	40	Ω
V_{hys}	All inputs				0.2		V
I_I	V_{CC} = 5.25 V,	$V_{IN} = V_{CC}$				5	µA
I_{IH}	V_{CC} = 5.25 V,	V_{IN} = 2.7 V				±1	µA
I_{IL}	V_{CC} = 5.25 V,	V_{IN} = 0.5 V				±1	µA
I_{OS}[‡]	V_{CC} = 5.25 V,	V_{OUT} = 0 V		–60	–120	–225	mA
I_{off}	V_{CC} = 0 V,	V_{OUT} = 4.5 V				±1	µA
I_{OZH}	V_{CC} = 5.25 V,	V_{OUT} = 2.7 V				10	µA
I_{OZL}	V_{CC} = 5.25 V,	V_{OUT} = 0.5 V				–10	µA
I_{CC}	V_{CC} = 5.25 V,	$V_{IN} \le 0.2$ V,	$V_{IN} \ge V_{CC} - 0.2$ V		0.1	0.2	mA
ΔI_{CC}	V_{CC} = 5.25 V, V_{IN} = 3.4 V[§], f_1 = 0, Outputs open				0.5	2	mA
I_{CCD}[¶]	V_{CC} = 5.25 V, One input switching at 50% duty cycle, Outputs open, $\overline{\text{OE}}_1$ or $\overline{\text{OE}}_2$ = GND, $V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V,				0.06	0.12	mA/ MHz
I_C[#]	V_{CC} = 5.25 V, Outputs open, $\overline{\text{OE}}_1$ or $\overline{\text{OE}}_2$ = GND	One bit switching at f_1 = 10 MHz at 50% duty cycle	$V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V		0.7	1.4	mA
			V_{IN} = 3.4 V or GND		1	2.4	
		Ten bits switching at f_1 = 2.5 MHz at 50% duty cycle	$V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V		1.6	3.2[‖]	
			V_{IN} = 3.4 V or GND		4.1	13.2[‖]	
C_i					5	10	pF
C_o					9	12	pF

[†] Typical values are at V_{CC} = 5 V, T_A = 25°C.

[‡] Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

[§] Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

[¶] This parameter is derived for use in total power-supply calculations.

[#] $I_C = I_{CC} + \Delta I_{CC} \times D_H \times N_T + I_{CCD} (f_0/2 + f_1 \times N_1)$

Where:

I_C = Total supply current
I_{CC} = Power-supply current with CMOS input levels
ΔI_{CC} = Power-supply current for a TTL high input (V_{IN} = 3.4 V)
D_H = Duty cycle for TTL inputs high
N_T = Number of TTL inputs at D_H
I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)
f_0 = Clock frequency for registered devices, otherwise zero
f_1 = Input signal frequency
N_1 = Number of inputs changing at f_1

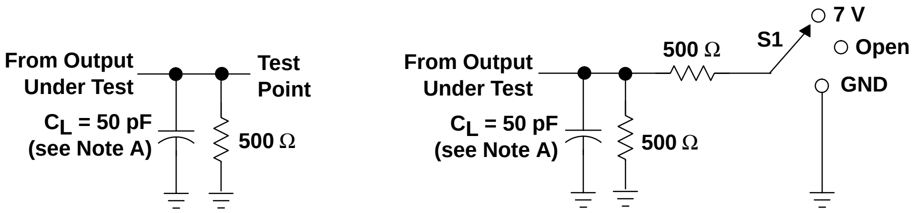
All currents are in milliamperes and all frequencies are in megahertz.

[‖] Values for these conditions are examples of the I_{CC} formula.

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST LOAD	CY74FCT2827AT		CY74FCT2827CT		UNIT
				MIN	MAX	MIN	MAX	
t_{PLH}	D	Y	C_L = 50 pF, R_L = 500 Ω	1.5	8	1.5	4.4	ns
t_{PHL}				1.5	8	1.5	4.4	
t_{PLH}	D	Y	C_L = 300 pF, R_L = 500 Ω	1.5	15	1.5	10	ns
t_{PHL}				1.5	15	1.5	10	
t_{PZH}	$\overline{OE}$	Y	C_L = 50 pF, R_L = 500 Ω	1.5	12	1.5	7	ns
t_{PZL}				1.5	12	1.5	7	
t_{PZH}	$\overline{OE}$	Y	C_L = 300 pF, R_L = 500 Ω	1.5	23	1.5	14	ns
t_{PZL}				1.5	23	1.5	14	
t_{PHZ}	$\overline{OE}$	Y	C_L = 5 pF, R_L = 500 Ω	1.5	9	1.5	5.7	ns
t_{PLZ}				1.5	9	1.5	5.7	
t_{PHZ}	$\overline{OE}$	Y	C_L = 50 pF, R_L = 500 Ω	1.5	9	1.5	6	ns
t_{PLZ}				1.5	9	1.5	6	

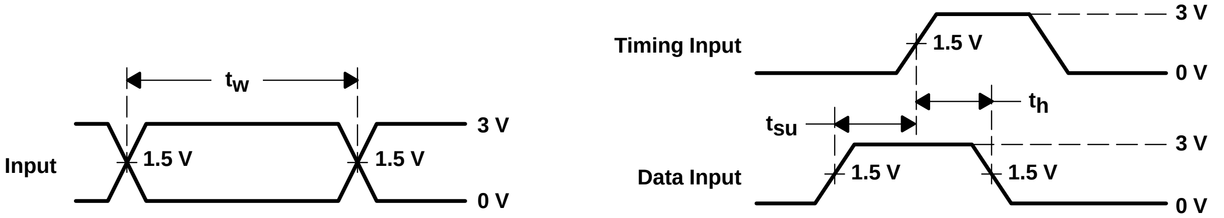
PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT FOR
TOTEM-POLE OUTPUTS

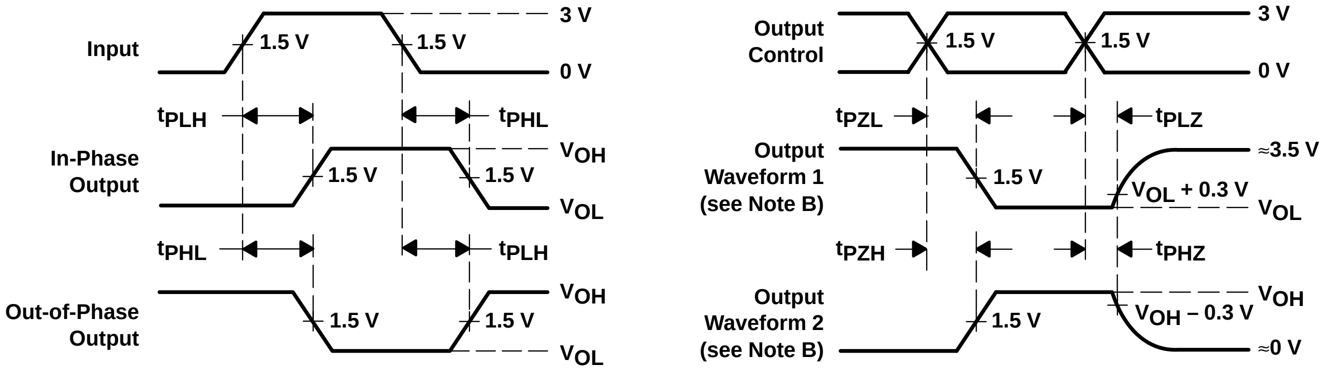
LOAD CIRCUIT FOR
3-STATE OUTPUTS

TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open



VOLTAGE WAVEFORMS
PULSE DURATION

VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES:
- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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